

<b>Notice of References Cited</b>	Application/Control No. 10/776,278		Applicant(s)/Patent Under Reexamination MARUYAMA ET AL.	
	Examiner Binh X. Tran		Art Unit 1792	Page 1 of 1

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*	B	US-2004/0081759	04-2004	Maruyama et al.	427/256
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